CURRENTS
LIMITED BY SPACE GHARGES
IN GLASS-LIKE CHALCOGENIDE
SEMICONDUCTORS OF THE Se<sub>95</sub>As<sub>5</sub>
SYSTEM CONTAINING Sm IMPURITY

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Summary

We have established that the transfer of charge carriers (holes) in the Al–Se<sub>95</sub>As<sub>5</sub>–Te structure is carried out by the mechanism of a monopolar injection current limited by space charges in the presence of two groups of traps [shallow traps  $(E_{t_1})$  corresponding to charged intrinsic defects  $C_1^-$  due to the broken bonds of Se and deep traps  $(E_{t_2})$  corresponding to charged intrinsic defects  $P_2^-$  due to As atoms with broken coordination]. It is shown that the Sm impurity influences strongly both the mechanism of formation of the current flow path and the trap parameters (energy position and concentration); especially, it influences the parameters of deep traps.